

Resource Summary Report

Generated by [RRID](#) on Aug 6, 2026

FEI: Hyperion II System

RRID:SCR_019885

Type: Tool

Proper Citation

FEI: Hyperion II System (RRID:SCR_019885)

Resource Information

URL: <https://www.fei.com/products/efa/hyperion-II-for-semiconductors/>

Proper Citation: FEI: Hyperion II System (RRID:SCR_019885)

Description: Electrical failure analysis system for semiconductors that offers transistor probing for electrical characterization and fault localization in support of semiconductor technology development, yield engineering and device reliability improvement.

Resource Type: instrument resource

Keywords: FEI, EFA System, Instrument Equipment, USEDit,

Availability: Commercially available

Resource Name: FEI: Hyperion II System

Resource ID: SCR_019885

Alternate IDs: Model_Number_Hyperion_II

Record Creation Time: 20220129T080347+0000

Record Last Update: 20260801T190634+0000

Ratings and Alerts

No rating or validation information has been found for FEI: Hyperion II System.

No alerts have been found for FEI: Hyperion II System.

Data and Source Information

Source: [SciCrunch Registry](#)

Usage and Citation Metrics

We have not found any literature mentions for this resource.